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 The scaling limits of the non critical strip wetting model.

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Abstract

The strip wetting model is defined by giving a (continuous space) one dimensional random walk S a reward β each time it hits the strip $\mathbb{R}^+ \times [0,a]$ (where a is a positive parameter), which plays the role of a defect line. We show that this model exhibits a phase transition between a delocalized regime ($\beta < \beta_c^a$) and a localized one ($\beta > \beta_c^a$), where the critical point $\beta_c^a > 0$ depends on S and on a. In this paper we give a precise pathwise description of the transition, extracting the full scaling limits of the model. Our approach is based on Markov renewal theory.

Keywords: scaling limits for physical systems, fluctuation theory for random walks, Markov renewal theory.

2000 MSC: 60K15, 60K20, 60K05, 82B27, 60K35, 60F17.

1. Introduction and main results

1.1. Definition of the models

We consider $(S_n)_{n\geq 0}$ a random walk such that $S_0:=0$ and $S_n:=\sum_{i=1}^n X_i$ where the X_i 's are i.i.d. and X_1 has a density $h(\cdot)$ with respect to the Lebesgue measure. We denote by \mathbf{P} the law of S, and by \mathbf{P}_x the law of the same process starting from x. We assume that $h(\cdot)$ is continuous and bounded on \mathbb{R} , that $h(\cdot)$ is positive in a neighborhood of the origin, that $\mathbf{E}[X]=0$ and that $\mathbf{E}[X^2]=:\sigma^2\in(0,\infty)$. We fix a>0 in the sequel.

The fact that h is continuous and positive in the neighborhood of the origin entails that

$$n_0 := \inf_{n \in \mathbb{Z}^+} \left\{ (\mathbf{P}[S_n > a], \mathbf{P}[-S_n > a]) \in (0, 1)^2 \right\} < \infty.$$
 (1)

For N a positive integer, we consider the event $C_N := \{S_1 \geq 0, \dots, S_N \geq 0\}$. We define the probability law (the *free wetting model in a strip*) $\mathbf{P}_{N,a,\beta}^f$ on \mathbb{R}^N by

$$\frac{d\mathbf{P}_{N,a,\beta}^f}{d\mathbf{P}} := \frac{1}{Z_{N,a,\beta}^f} \exp\left(\beta \sum_{k=1}^N \mathbf{1}_{S_k \in [0,a]}\right) \mathbf{1}_{\mathcal{C}_N}$$
(2)

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